

Enhancement Mode N-Channel Power MOSFET

 $TO-220/NMOS/30V/\pm20V/1.5V/100A/4.1m\Omega$

Rev0.5





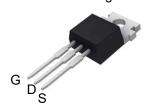
30V, 4.1mΩ, 100A, N-Channel MOSFET

1.Features

- ◆ 30V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V

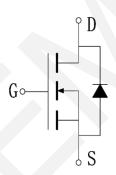
2.Applications

- ◆ Power Switching Application
- Load Switching



TO-220 Pin Description

V_{DS}	R _{DS(on)} Typ.	I _D Max.	
30V	4.1mΩ @ 10V	4004	
	5.7mΩ @ 4.5V	100A	



Schematic Diagram

Part no.	Marking	Package	PCS/Tube	PCS/CTN.
WP30100KFB	WP30100K	TO-220	50	5,000

3. Package Marking and Ordering Information

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	30	V
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC)	I _D	100	Α
Drain Current (Pulse), PW≤300μs	I _{DP}	400	Α
Total Dissipation	P _D	65	W
Avalanche Energy, Single Pulsed	E _{AS}	196	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	R _{eJC}	2.3	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

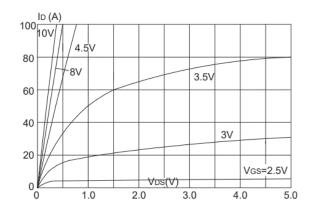
6.Electrical Characteristics at Ta=25°C (Note 3)

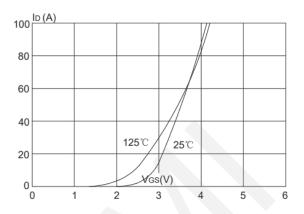
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	I _D = 250μA, V _{GS} = 0V	30	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V	-	-	100	nA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _{DS} =250μA	1.0	1.5	2.5	V
Static Drain to Source On-State	-	I _D = 30A, V _{GS} = 10V	-	4.1	5.0	mΩ
Resistance	R _{DS(on)}	I _D = 20A, V _{GS} = 4.5V	-	5.7	8.5	mΩ
Forward Transconductance	G _{FS}	I _D = 20A, V _{DS} = 5V	20	-	-	S
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz	-	2764	-	pF
Output Capacitance	Coss		-	260	-	pF
Reverse Transfer Capacitance	C _{rss}		-	228	-	pF
Turn-ON Delay Time	t _{d(on)}		-	21	-	ns
Rise Time	t _r	$V_{DS} = 15V, I_D = 30A,$	-	32	-	ns
Turn-OFF Delay Time	$t_{\sf d(off)}$	V_{GS} = 10V, R_G = 3 Ω	-	60	-	ns
Fall Time	t _f		-	34	-	ns
	Qg	V _{DS} = 15V, V _{GS} = 10V, I _D = 30A	-	38	-	nC
Total Gate Charge	Q _{gs}		-	5	-	nC
	Q _{gd}		-	10	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 30A, V _{GS} = 0	0.5	0.85	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

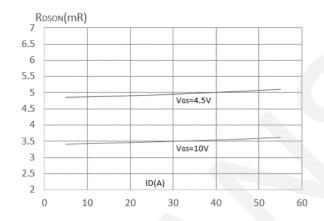


7. Typical electrical and thermal characteristics

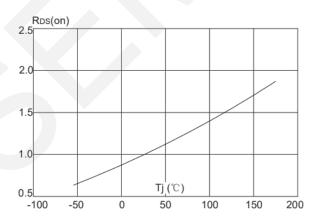




Output Characteristics

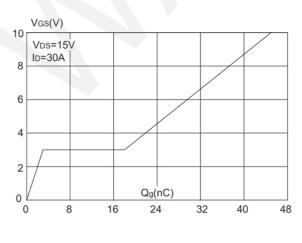


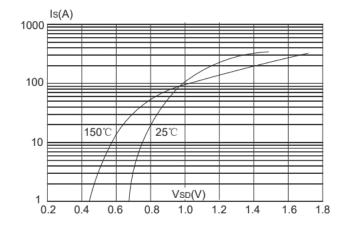
Transfer Characteristics



Rdson-Drain Current

Rdson-Junction Temperature

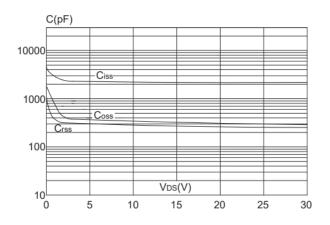


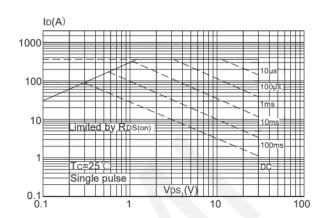


Gate Charge

Source-Drain Diode Forward

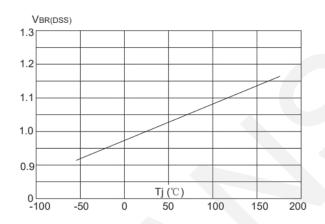


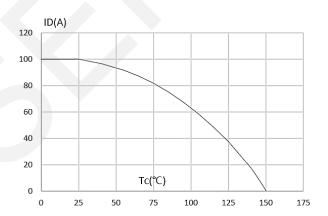




Capacitance vs Vds

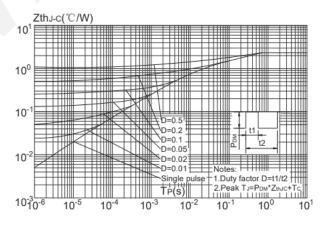
Safe Operation Area





BV_{DSS} vs Junction Temperature

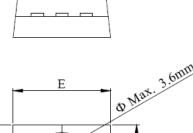
Maximum Continuous Drain Current vs. Case Temperature

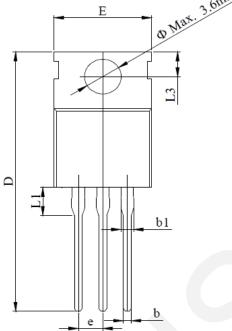


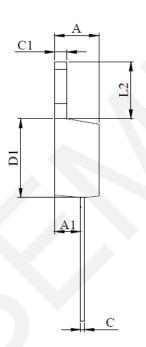
Normalized Maximum Transient Thermal Impedance



8.Package Dimensions







DIM		MILLIMETER	
DIM.	MIN.	NOM.	MAX.
A	4.24		4.70
A1	2.20		3.00
b	0.70		0.95
b1	1.14		1.70
С	0.40		0.60
C1	1.15		1.40
D	28.00		29.80
D1	8.80		9.90
Е	9.70		10.50
L1			3.80
L2	6.25		6.90
L3	2.40		3.00
e		2.54 BSC	



9. Important Notice

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